

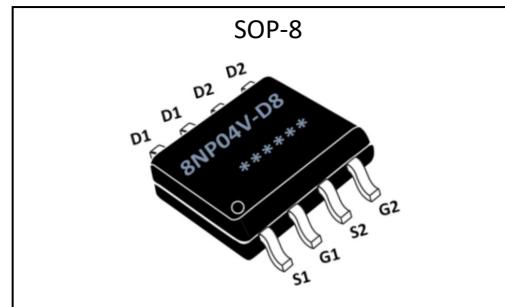
General Description

The GL8NP04V-D8 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is SOP-8, which accords with the RoHS standard.

	N-Channel	P-Channel	Units
V_{DSS}	40	-40	V
I_D	8	-8	A
P_D	2	2	W
$R_{DS(ON)type}$	14	26	$m\Omega$

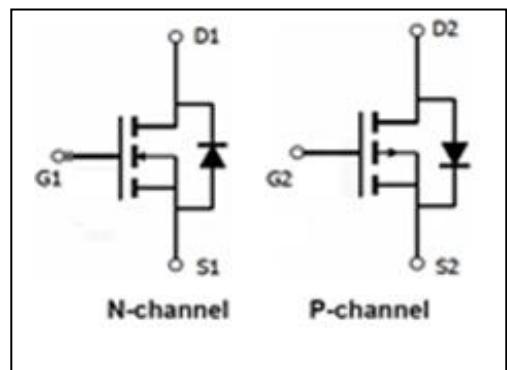
Features

- N-Channel:
 $R_{DS(ON)} < 18m\Omega$ @ $V_{GS}=10V$ (Typ14mΩ)
- P-Channel:
 $R_{DS(ON)} < 33m\Omega$ @ $V_{GS}=10V$ (Typ26mΩ)
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation



Applications

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Absolute (Tc= 25°C unless otherwise specified)

Symbol	Parameter	N-Channel	P-Channel	Units
V_{DSS}	Drain-to-Source Voltage	40	-40	V
I_D	Continuous Drain Current	8	-8	A
I_{DM}	Pulsed Drain Current	40	-40	A
V_{GS}	Gate-to-Source Voltage	± 20	± 20	V
P_D	Power Dissipation	2	2	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55 to 150	-55 to 150	°C



GL8NP04V-D8

GL Silicon N+P Channel Power MOSFET

N-CH Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	40	--	--	V
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=40\text{V}, V_{GS}=0\text{V}, T_a=25^\circ\text{C}$	--	--	1.0	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+10\text{V}$	--	--	0.1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-10\text{V}$	--	--	-0.1	μA

ON Characteristics ^{a3}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10\text{V}, I_D=8\text{A}$	--	14	18	$\text{m}\Omega$
$V_{GS(\text{TH})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	1.5	2.0	V

Pulse width $t_p \leq 380\mu\text{s}, \delta \leq 2\%$

Dynamic Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=8\text{A}$	30	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}$	--	415	--	pF
C_{oss}	Output Capacitance	$f=1.0\text{MHz}$	--	115	--	
C_{rss}	Reverse Transfer Capacitance		--	11	--	

Resistive Switching Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time		--	4.5	--	ns
t_r	Rise Time	$V_{DD}=15\text{V}, R_L=2.5\Omega$	--	3.0	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS}=10\text{V}, R_G=3\Omega$	--	14.5	--	
t_f	Fall Time		--	3.0	--	
Q_g	Total Gate Charge	$V_{DD}=20\text{V}, I_D=8\text{A}$	--	12	--	nC
Q_{gs}	Gate to Source Charge	$V_{GS}=10\text{V}$	--	3.2	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	3.1	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current ^{a2} (Body Diode)		--	--	6	A
V_{SD}	Diode Forward Voltage ^{a3}	$I_S=6\text{A}, V_{GS}=0\text{V}$	--	--	1.2	V



GL8NP04V-D8

GL Silicon N+P Channel Power MOSFET

P-CH Electrical Characteristics (T_C= 25°C unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	-40	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =-40V, V _{GS} = 0V, T _a =25°C	--	--	-1.0	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+10V	--	--	-0.1	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-10V	--	--	0.1	μA

ON Characteristics ^{a3}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DSON}	Drain-to-Source On-Resistance	V _{GS} =-10V, I _D =-5A	--	26	36	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-1.0	-1.5	-2.0	V

Pulse width tp≤380μs, δ≤2%

Dynamic Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =-5V, I _D =-5A	10	--	--	S
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-20V	--	940	--	pF
C _{oss}	Output Capacitance	f=1.0MHz	--	97	--	
C _{rss}	Reverse Transfer Capacitance		--	72	--	

Resistive Switching Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time		--	6.2	--	ns
t _r	Rise Time	V _{DD} =-20V, R _L =2.3Ω	--	8.4	--	
t _{d(OFF)}	Turn-Off Delay Time	V _{GS} =-10V, R _G =6Ω	--	44.8	--	
t _f	Fall Time		--	16	--	
Q _g	Total Gate Charge	V _{DD} =-20V, I _D =-5A	--	17	--	nC
Q _{gs}	Gate to Source Charge	V _{GS} =-10V	--	3.4	--	
Q _{gd}	Gate to Drain ("Miller")Charge		--	3.2	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current ^{a2} (Body Diode)		--	--	-6	A
V _{SD}	Diode Forward Voltage ^{a3}	I _S =-6A, V _{GS} =0V	--	--	-1.2	V

Wuxi Guang Lei electronic technology co., LTD



GL8NP04V-D8

GL Silicon N+P Channel Power MOSFET

Thermal Characteristics

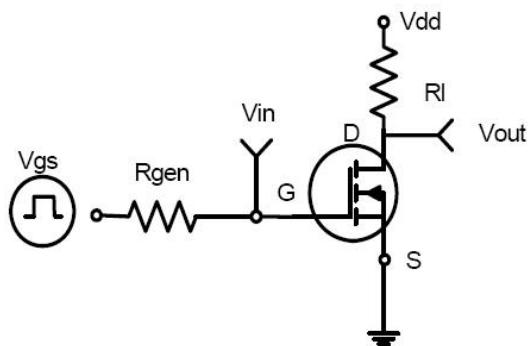
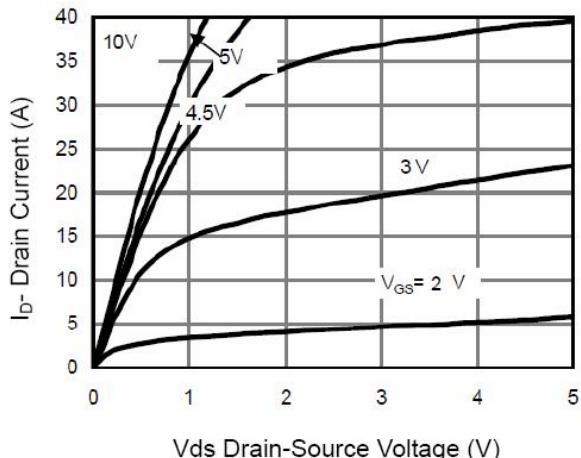
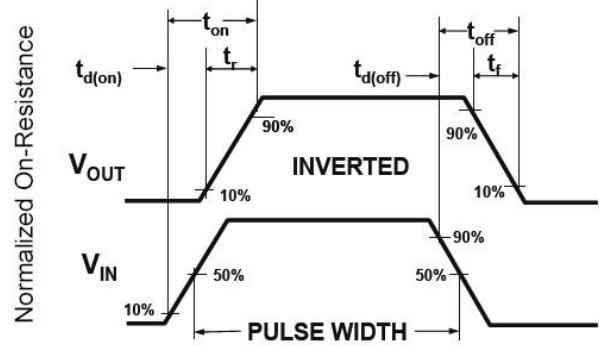
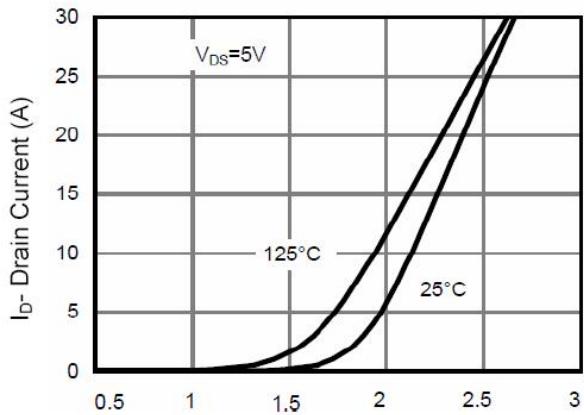
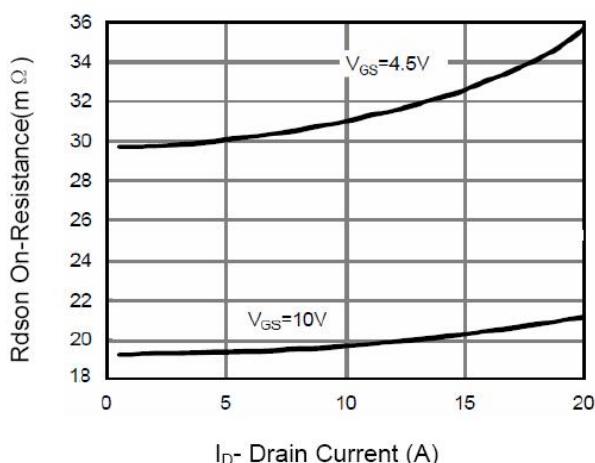
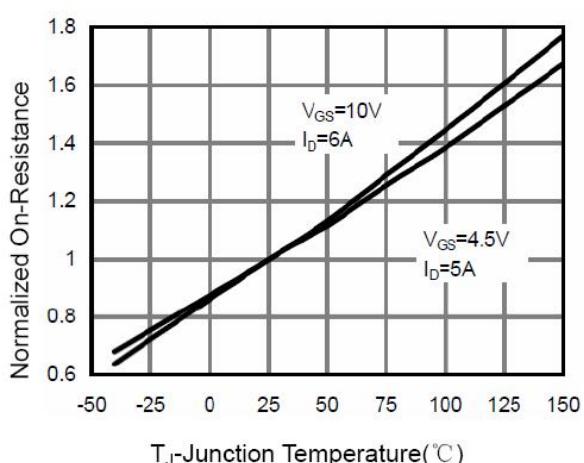
Symbol	Parameter	Typ.	Units
R _{θJA}	Junction-to-Case ^{a2} ,N-Ch	62.5	°C/W
R _{θJA}	Junction-to-Case ^{a2} ,P-Ch	62.5	°C/W

^{a1}: Repetitive Rating: Pulse width limited by maximum junction temperature.

^{a2}: Surface Mounted on FR4 Board, t≤10sec.

^{a3}: Pulse Test: Pulse Width≤300μs, Duty Cycle≤2%.

^{a4}: Guaranteed by design, not subject to production

N-Channel Characteristics Curves

Figure 1:Switching Test Circuit

Figure 3 Output Characteristics

Figure 2:Switching Waveforms

Figure 4 Transfer Characteristics

Figure 5 Drain-Source On-Resistance

Figure 6 Drain-Source On-Resistance

GL Silicon N+P Channel Power MOSFET

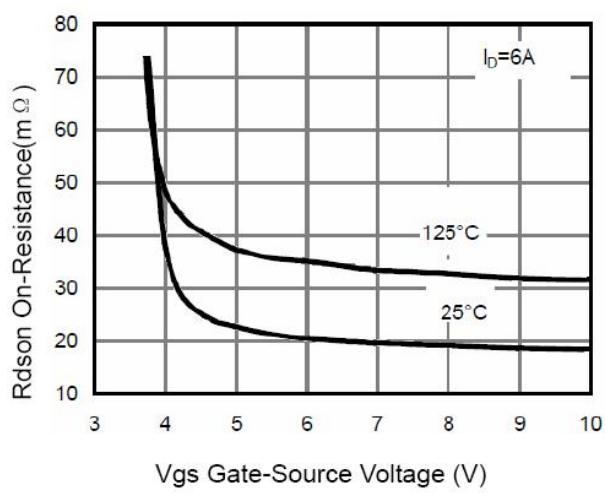


Figure 7 Rdson vs Vgs

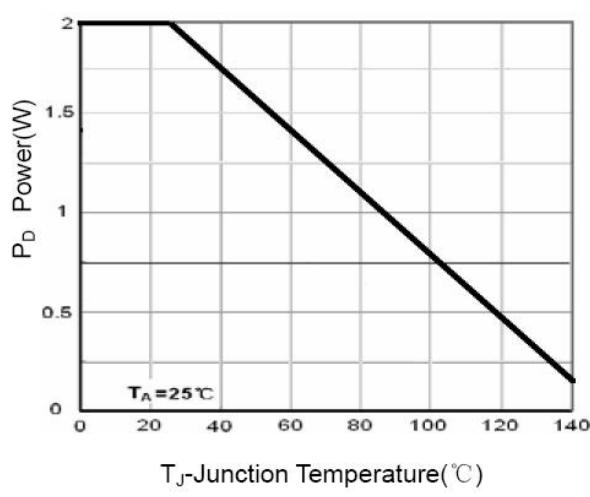


Figure 8 Power Dissipation

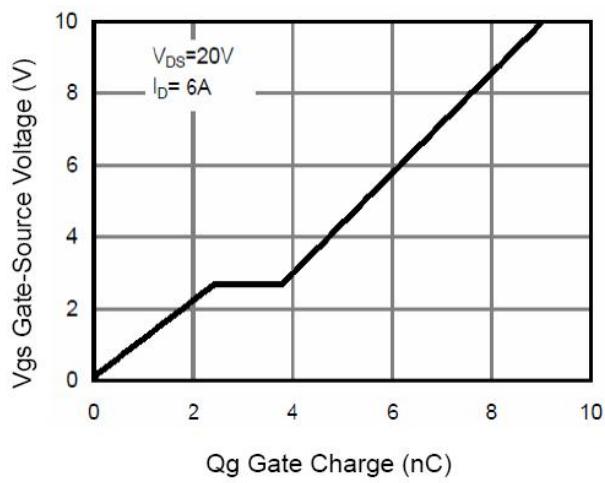


Figure 9 Gate Charge

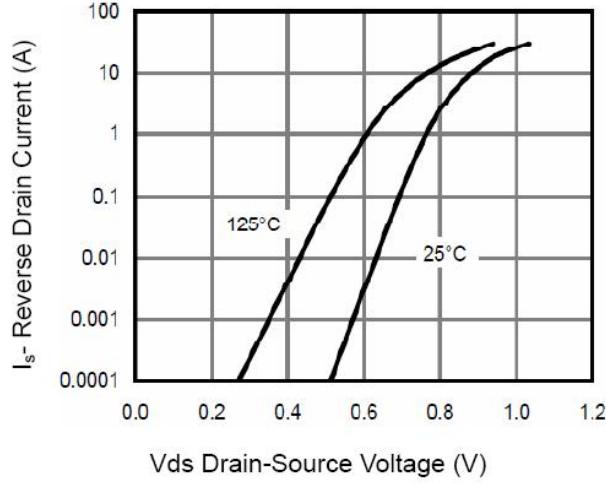


Figure 10 Source- Drain Diode Forward

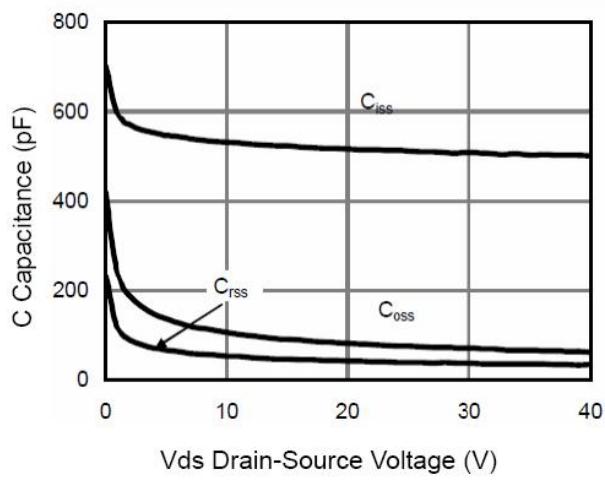


Figure 11 Capacitance vs Vds

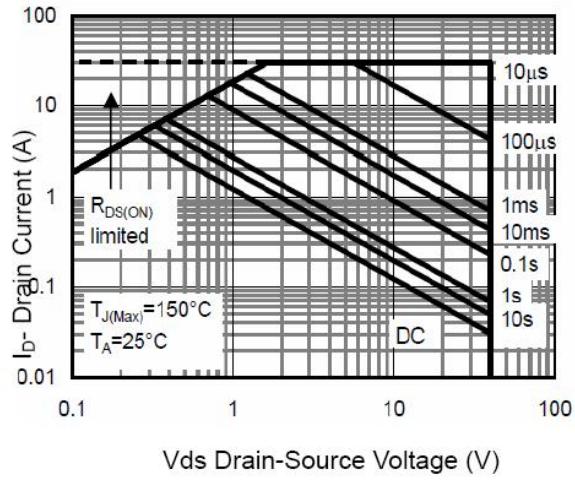


Figure 12 Safe Operation Area

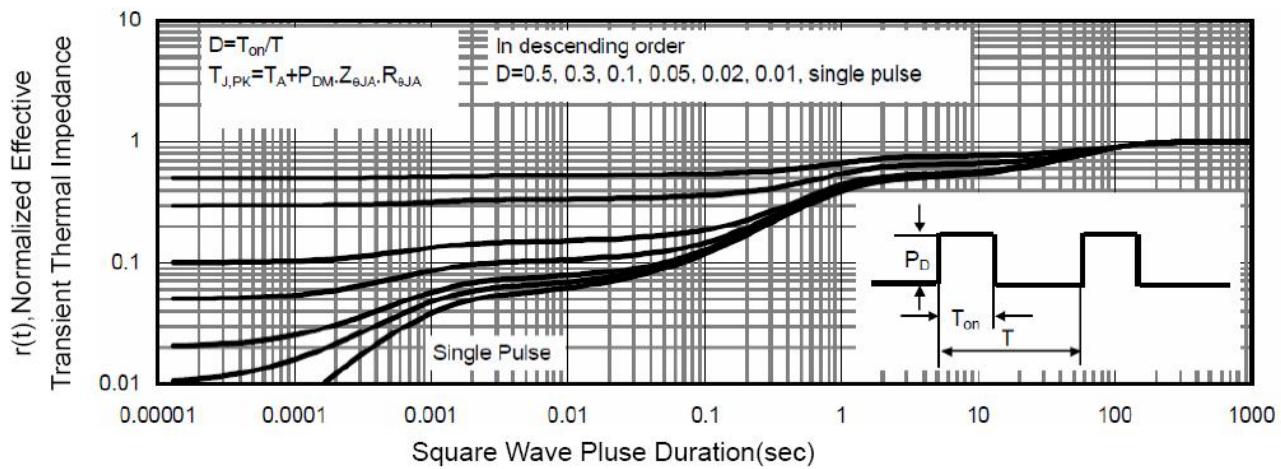
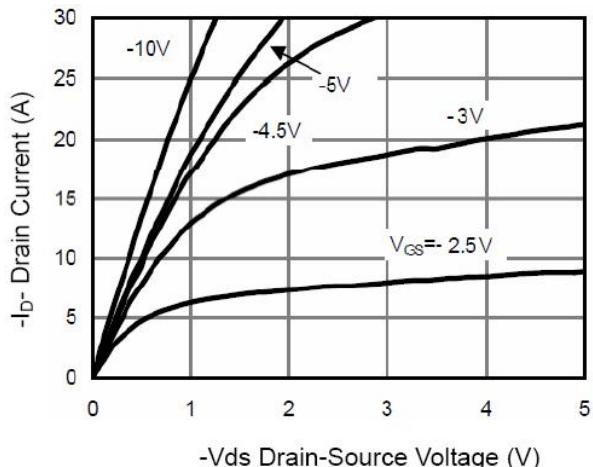
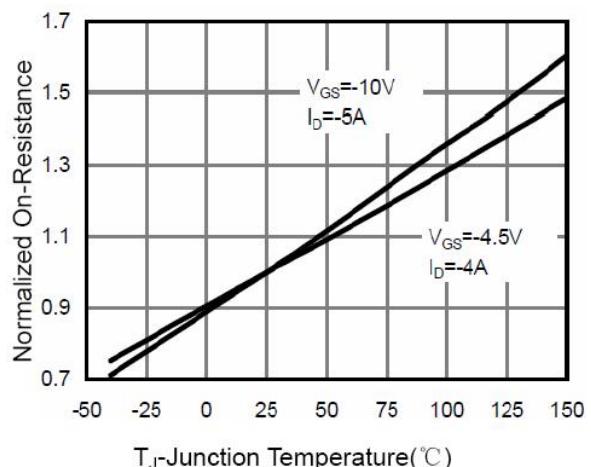
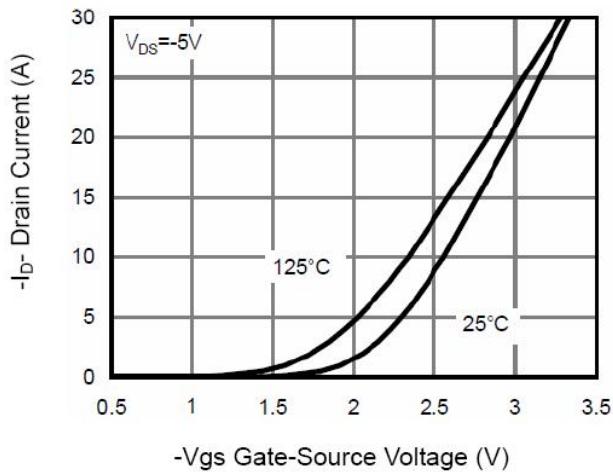
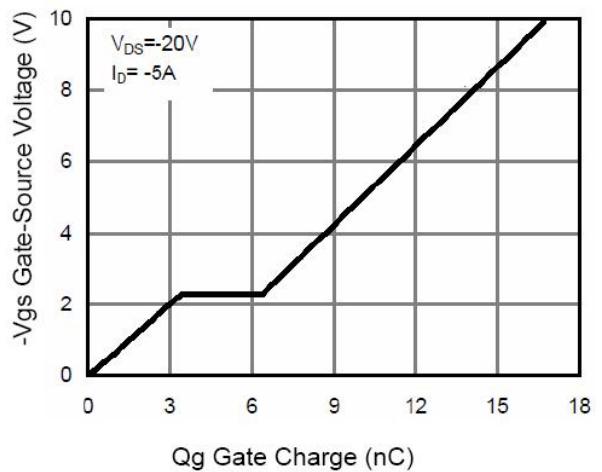
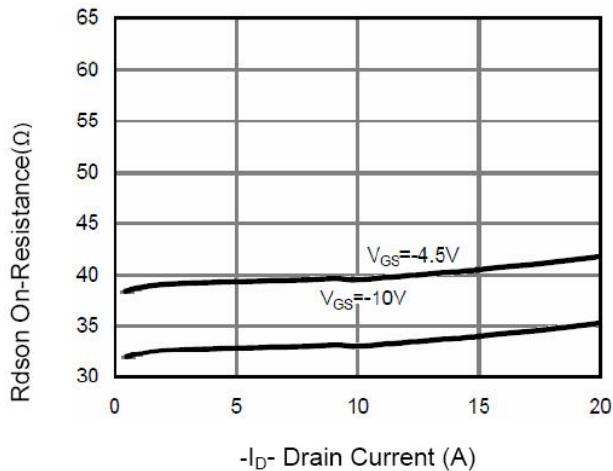
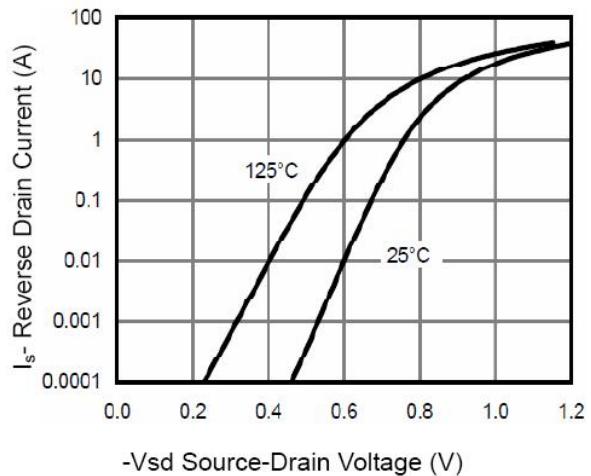
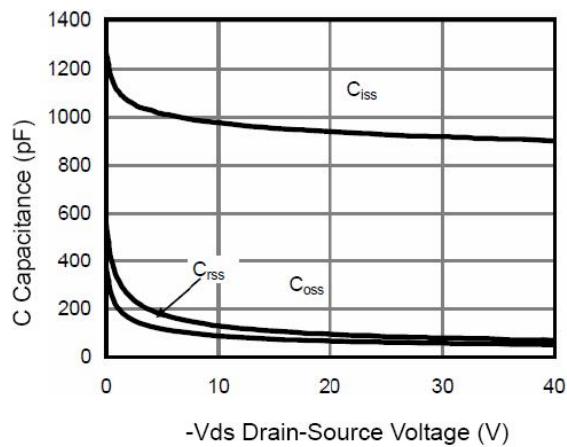
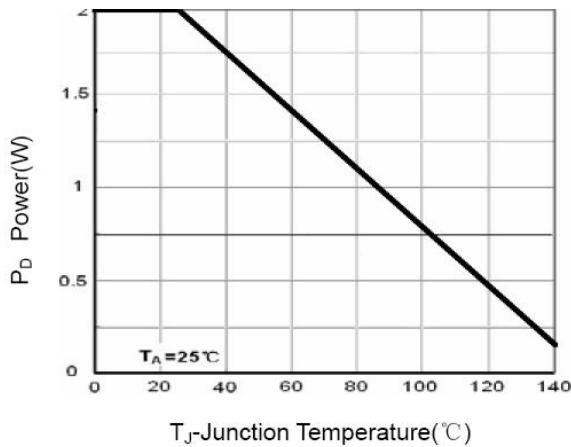
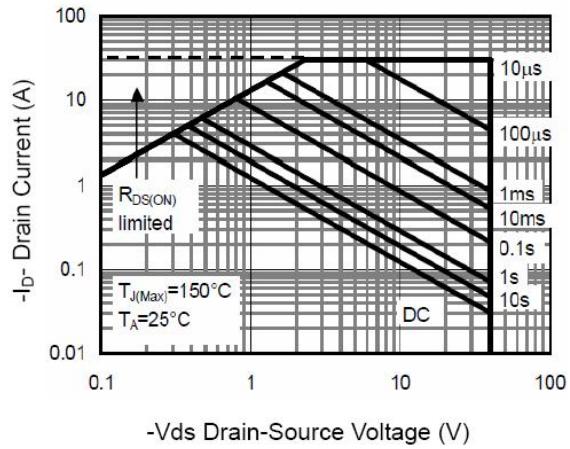
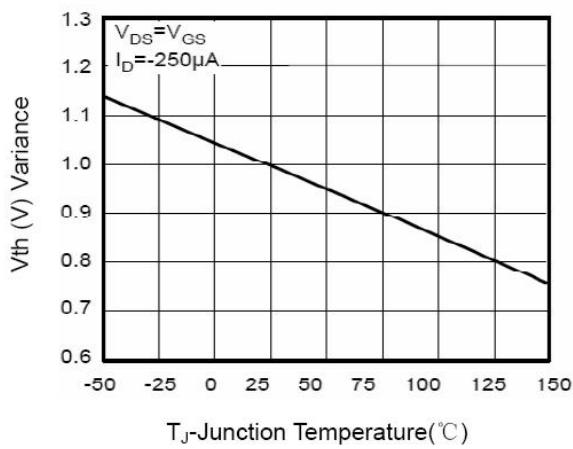
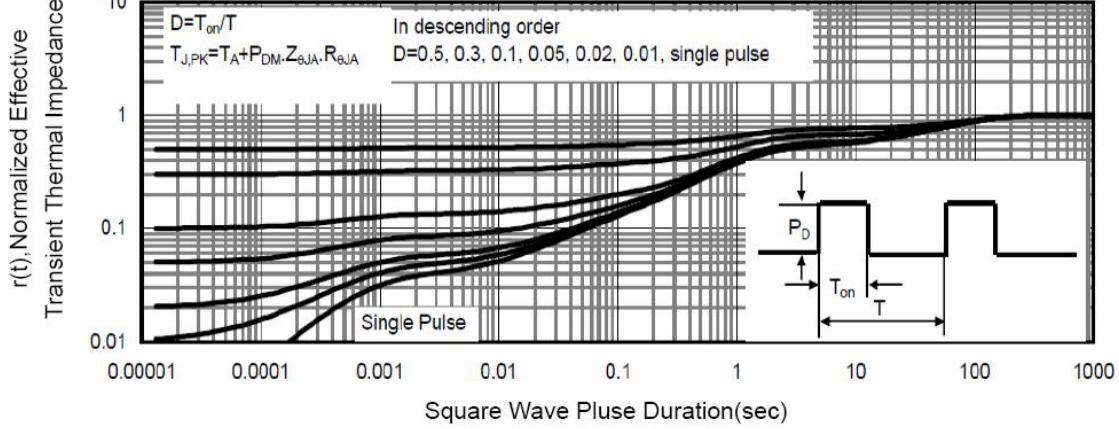


Figure 13 Normalized Maximum Transient Thermal Impedance

P-Channel Characteristics Curves

Figure 1 Output Characteristics

Figure 4 Rdson-Junction Temperature

Figure 2 Transfer Characteristics

Figure 5 Gate Charge

Figure 3 Rdson-Drain Current

Figure 6 Source-Drain Diode Forward

GL Silicon N+P Channel Power MOSFET

Figure 7 Capacitance vs Vds

T_J-Junction Temperature(°C)
Figure 9 Power Dissipation

Figure 8 Safe Operation Area

T_J-Junction Temperature(°C)
Figure 10 $V_{GS(th)}$ vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance

Company: Wuxi Guang Lei electronic technology co., LTD